


<b>Search Notes</b> 	<b>Application/Control No.</b> 10773480	<b>Applicant(s)/Patent Under Reexamination</b> DIB ET AL.
	<b>Examiner</b> Kim, Jennifer	<b>Art Unit</b> 1617

SEARCHED			
Class	Subclass	Date	Examiner
514	226.2	7/23/2007	jmk

SEARCH NOTES		
Search Notes	Date	Examiner
STIC ; inventor serach; STN (registry, medicine)	7/23/2007	jmk

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner